

Silicon Diffused Power Transistor

BU2532AL

GENERAL DESCRIPTION

New generation, high-voltage, high-speed switching npn transistor in a plastic envelope intended for use in horizontal deflection circuits of high resolution monitors up to 82 kHz.

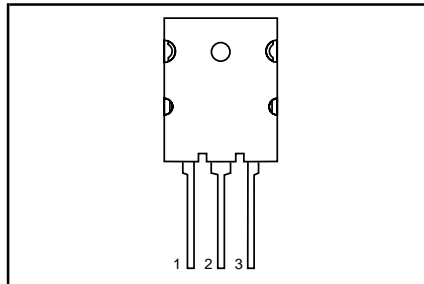
QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
V_{CESM}	Collector-emitter voltage peak value	$V_{BE} = 0$	-	1500	V
V_{CEO}	Collector-emitter voltage (open base)		-	800	V
I_C	Collector current (DC)		-	16	A
I_{CM}	Collector current peak value		-	40	A
P_{tot}	Total power dissipation	$T_{mb} \leq 25\text{ }^\circ\text{C}$	-	125	W
V_{CESat}	Collector-emitter saturation voltage	$I_C = 7.0\text{ A}; I_B = 1.17\text{ A}$	-	5.0	V
I_{Csat}	Collector saturation current		7	-	A
t_s	Storage time	$I_{Csat} = 7.0\text{ A}; I_{B(end)} = 1\text{ A}$	1.4	1.8	μs

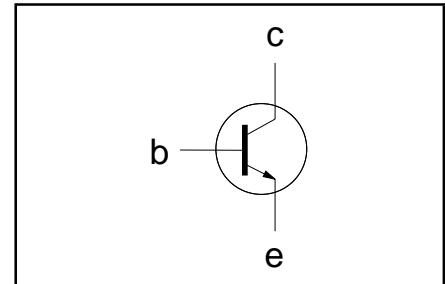
PINNING - SOT430

PIN	DESCRIPTION
1	base
2	collector
3	emitter
heat sink	collector

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum Rating System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CESM}	Collector-emitter voltage peak value	$V_{BE} = 0\text{ V}$	-	1500	V
V_{CEO}	Collector-emitter voltage (open base)		-	800	V
I_C	Collector current (DC)		-	16	A
I_{CM}	Collector current peak value		-	40	A
I_B	Base current (DC)		-	10	A
I_{BM}	Base current peak value		-	15	A
$-I_{B(AV)}$	Reverse base current	average over any 20 ms period	-	200	mA
$-I_{BM}$	Reverse base current peak value ¹		-	10	A
P_{tot}	Total power dissipation	$T_{mb} \leq 25\text{ }^\circ\text{C}$	-	125	W
T_{stg}	Storage temperature		-55	150	$^\circ\text{C}$
T_j	Junction temperature		-	150	$^\circ\text{C}$

THERMAL RESISTANCES

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
$R_{th\ j-mb}$	Junction to mounting base	-	-	1.0	K/W
$R_{th\ j-a}$	Junction to ambient	in free air	35	-	K/W

¹ Turn-off current.

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STATIC CHARACTERISTICS

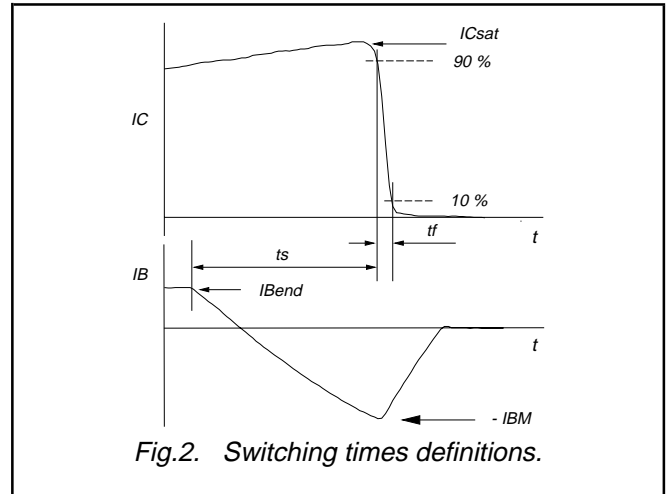
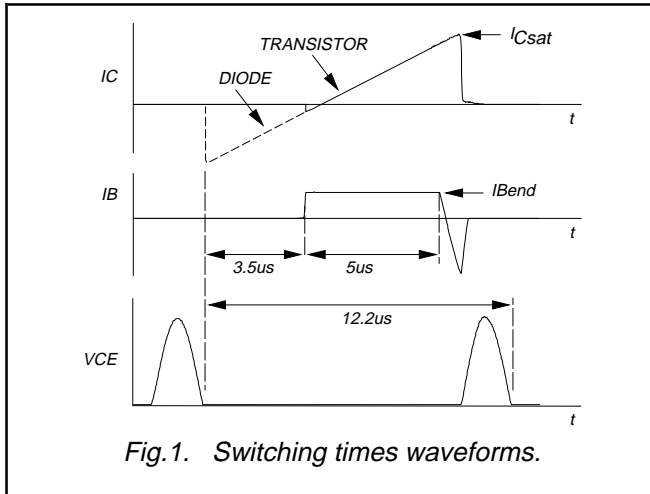
$T_{mb} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{CES}	Collector cut-off current ²	$V_{BE} = 0\text{ V}; V_{CE} = V_{CESMmax}$	-	-	1.0	mA
I_{CES}		$V_{BE} = 0\text{ V}; V_{CE} = V_{CESMmax}; T_j = 125\text{ }^{\circ}\text{C}$	-	-	2.0	mA
I_{EBO}	Emitter cut-off current	$V_{EB} = 7.5\text{ V}; I_C = 0\text{ A}$	-	-	1.0	mA
BV_{EBO}	Base-emitter breakdown voltage	$I_B = 1\text{ mA}$	7.5	14	-	V
V_{CEsat}	Collector-emitter saturation voltage	$I_C = 7.0\text{ A}; I_B = 1.17\text{ A}$	-	-	5.0	V
V_{BEsat}	Base-emitter saturation voltage	$I_C = 7.0\text{ A}; I_B = 1.17\text{ A}$	-	-	1.0	V
h_{FE}	DC current gain	$I_C = 1\text{ A}; V_{CE} = 5\text{ V}$	-	17	-	
h_{FE}		$I_C = 7\text{ A}; V_{CE} = 5\text{ V}$	6	9	12.5	

DYNAMIC CHARACTERISTICS

$T_{mb} = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

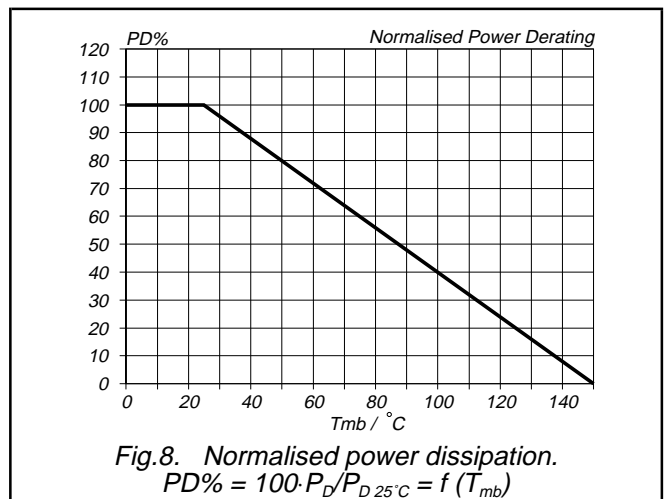
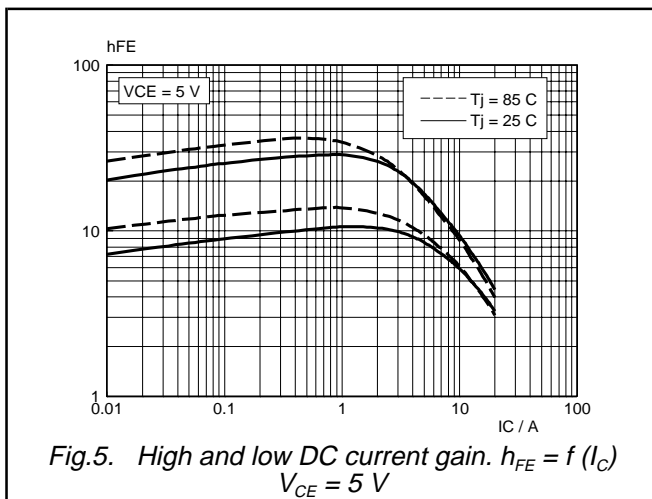
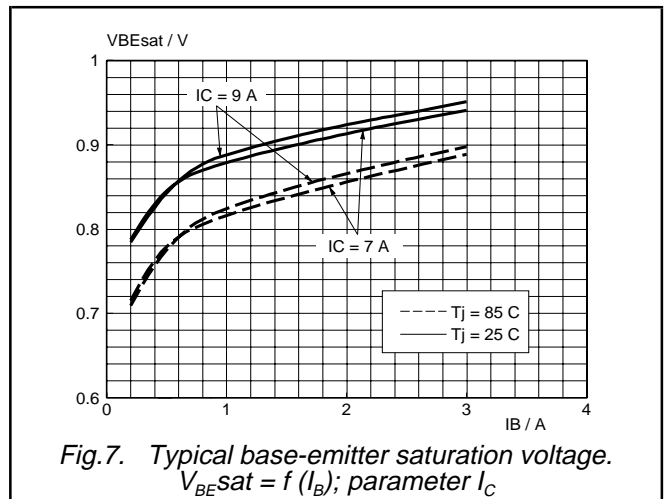
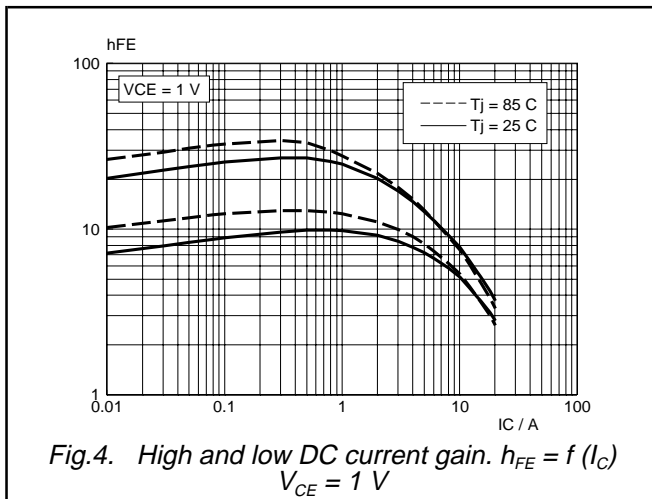
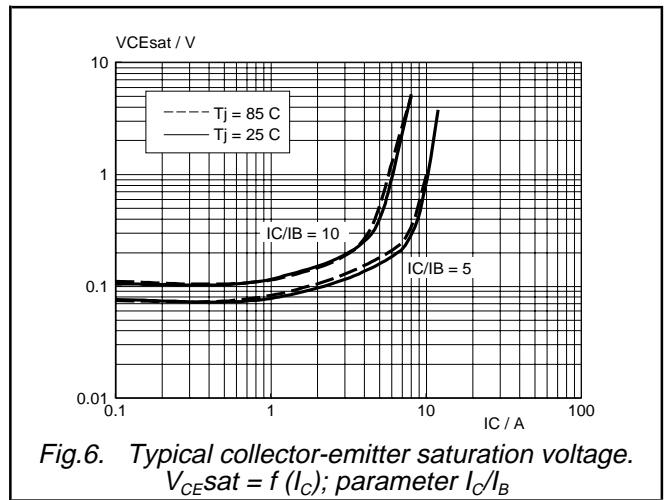
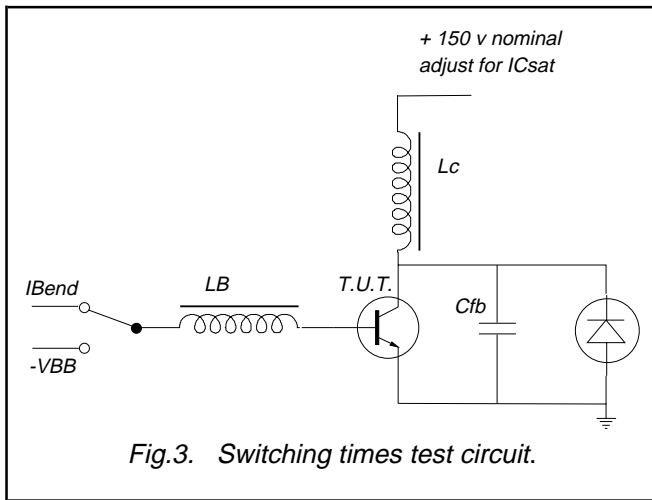
SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
t_s	Switching times (82 kHz line deflection dynamic test circuit). Turn-off storage time	$I_{Csat} = 7.0\text{ A}; L_C = 100\text{ }\mu\text{H}; C_{fb} = 3\text{ nF}; V_{CC} = 138\text{ V}; I_{B(end)} = 1.0\text{ A}$	1.4	1.8	μs
t_f	Turn-off fall time		0.06	0.1	μs



² Measured with half sine-wave voltage (curve tracer).

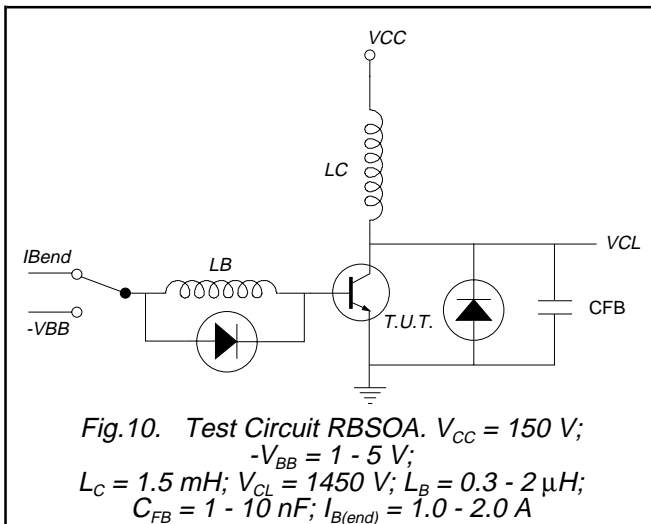
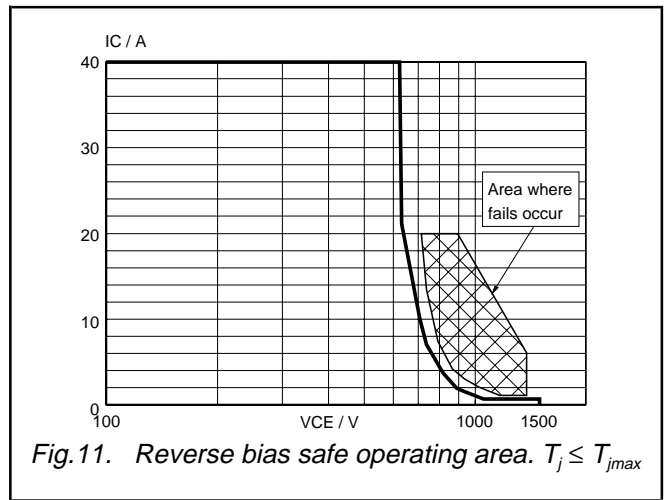
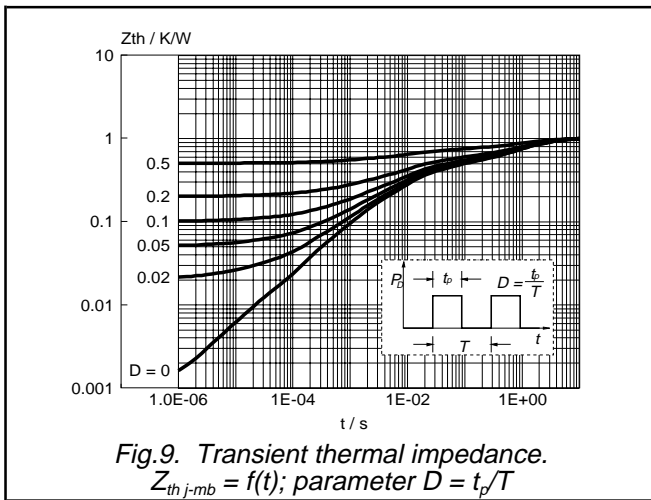
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MECHANICAL DATA

Dimensions in mm

Net Mass: 9 g

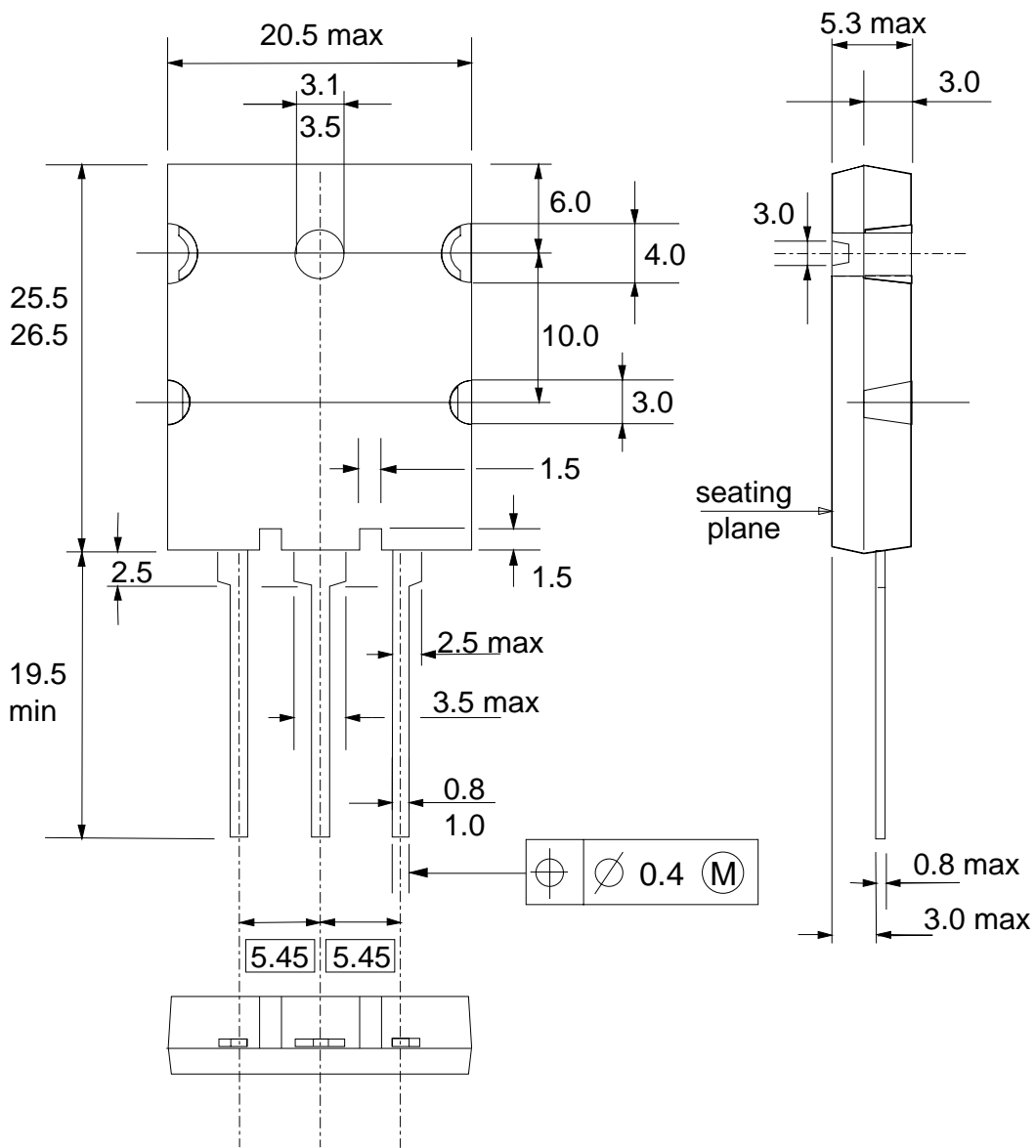


Fig.12. SOT430; pin 2 connected to mounting base.

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DEFINITIONS

Data sheet status	
Objective specification	This data sheet contains target or goal specifications for product development.
Preliminary specification	This data sheet contains preliminary data; supplementary data may be published later.
Product specification	This data sheet contains final product specifications.
Limiting values	
Limiting values are given in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of this specification is not implied. Exposure to limiting values for extended periods may affect device reliability.	
Application information	
Where application information is given, it is advisory and does not form part of the specification.	
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